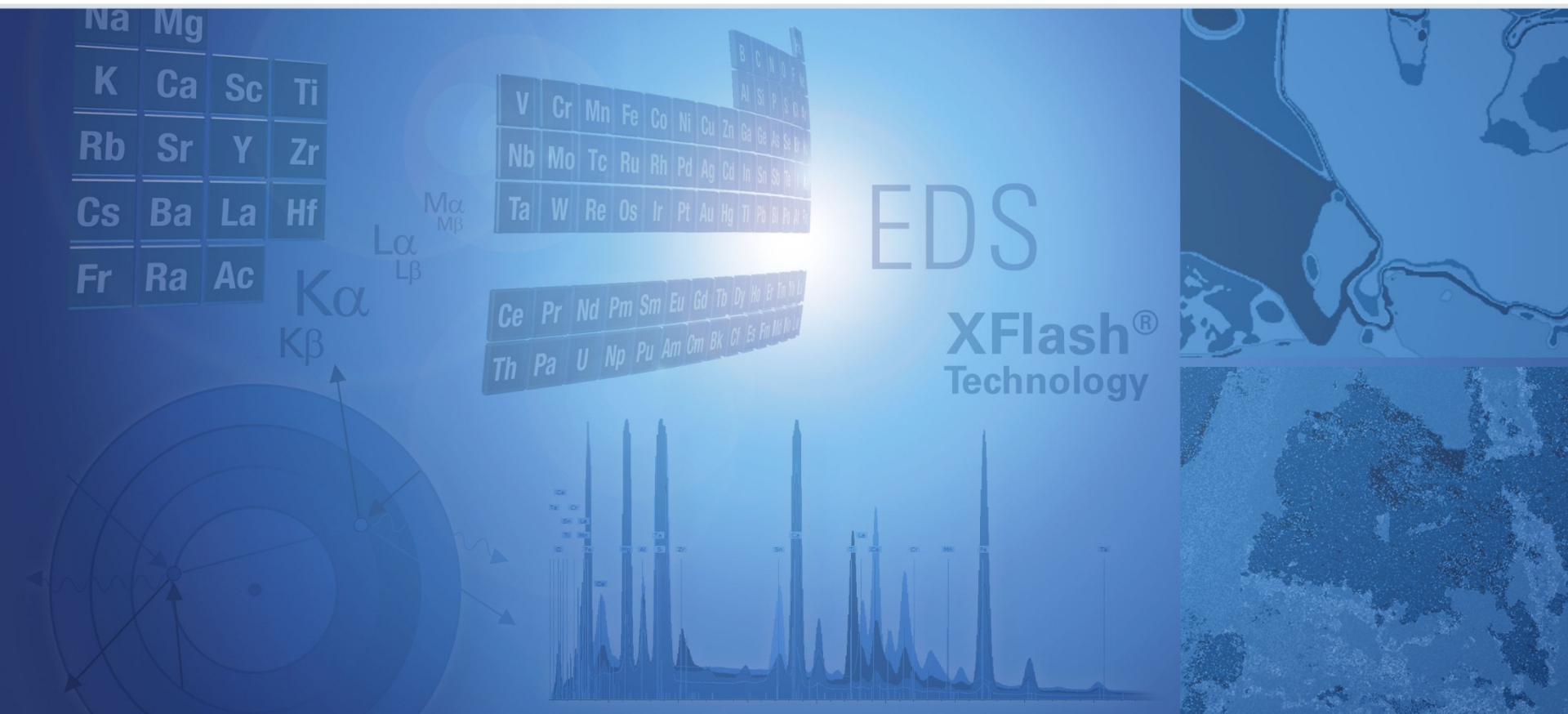


Heating experiments in STEM-EDS



Bruker Nano Analytics, Berlin, Germany
Webinar, August 29, 2018





Dr. Meiken Falke

Global Product Manager TEM
Bruker Nano Analytics, Berlin, Germany

Mauro Porcu

Marketing Manager
DENSsolutions, Delft, Netherlands

Dr. Igor Németh

Application Scientist, EDS
Bruker Nano Analytics, Berlin, Germany

Part 1. (S)TEM sample holder optimization

Mauro Porcu, DENSSolutions

- In-situ applications
- The new heating Nano-chip
- Wildfire product family

Part 2. Heating experiments (EDS mapping study at elevated temperatures) - Igor Németh, Bruker Nano

- IR effects under control: low energy threshold, peak broadening
- Demonstrate elemental mapping results up to 1000° C for the first time in literature
- Autophase results



INNOVATIONS THAT MATTER

The Wildfire solution: superior in situ TEM heating

Mauro Porcu, Marketing Manager

The power of In Situ TEM

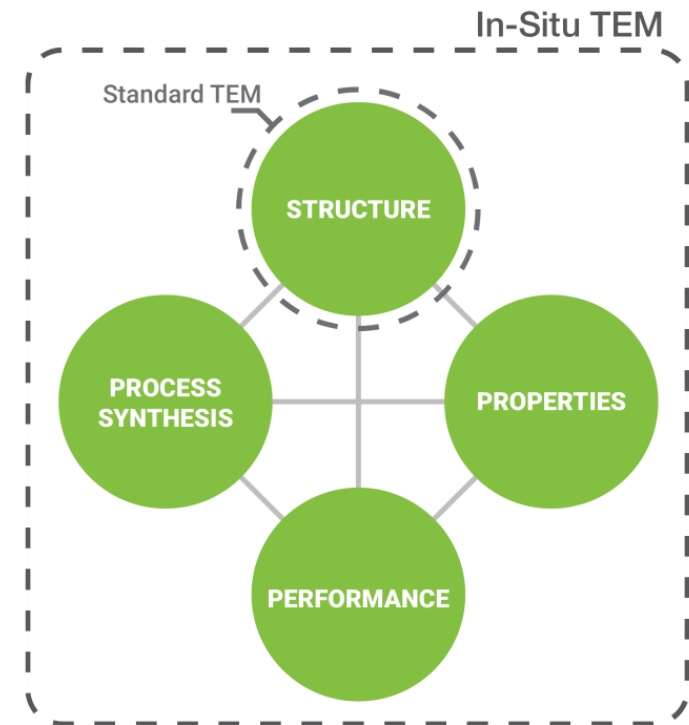
Traditional TEM



The power of In Situ TEM



In situ TEM



The benefit of in situ heating

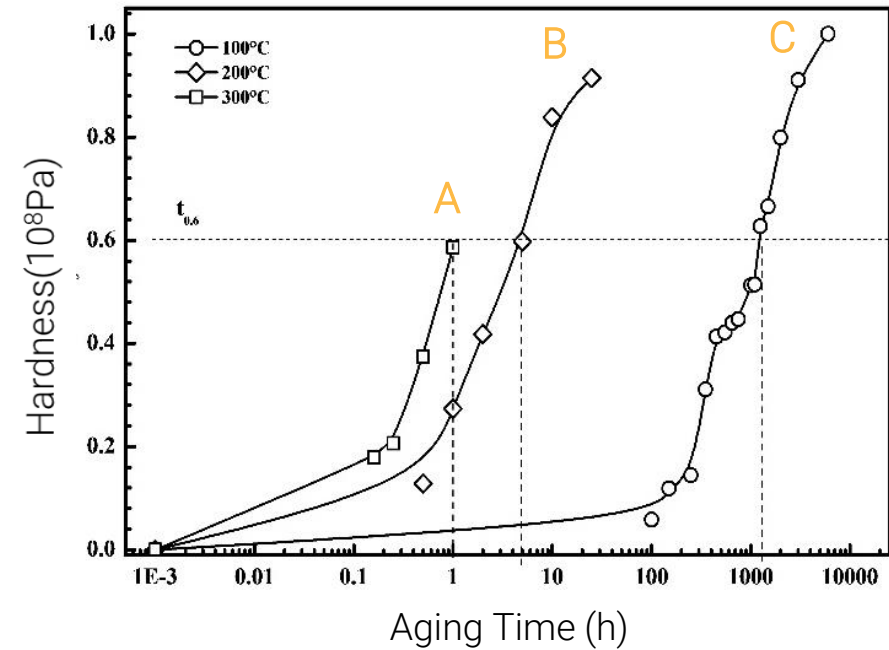
Precipitation hardening of metal alloys



Challenges:

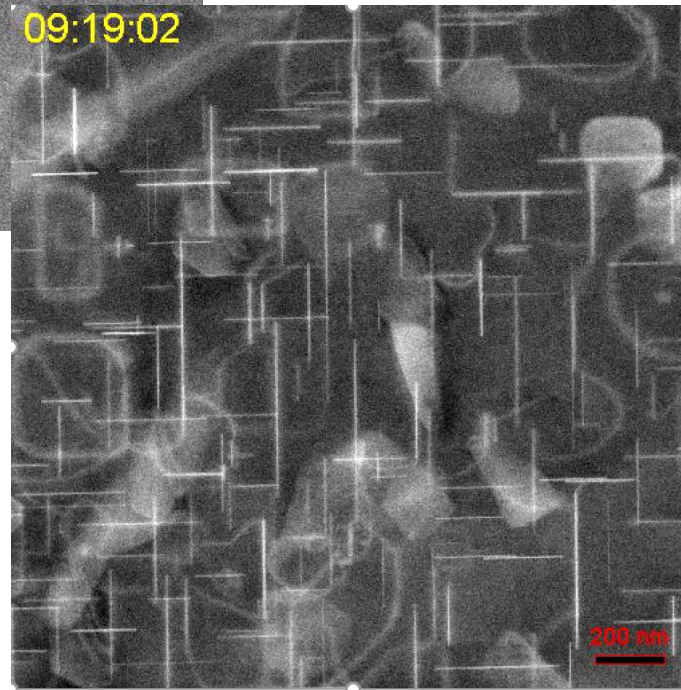
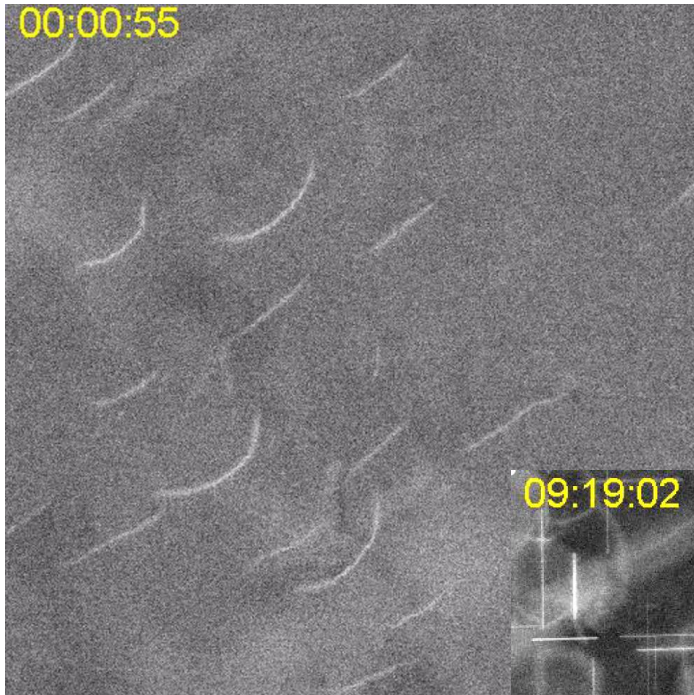
- Optimising heat treatments in the production process

Process and Property relation



Correlate structure with properties

Precipitation hardening of metal alloys



Challenges: Optimising heat treatments in the production process

Researcher:
Dr. C. Liu



TU Delft



Double tilt Heating



Conditions: FIB lamella, 140 – 200 °C, 20 hours, HAADF STEM

Results: Mechanism of the morphological evolution of the precipitates in Al alloys

Liu, Chunhui, et al. *Scientific reports* 7 (2017).

Correlate structure with properties

Precipitation hardening of metal alloys



Challenges: Optimising heat treatments in the production process

Researcher:
Dr. C. Liu



Double tilt Heating

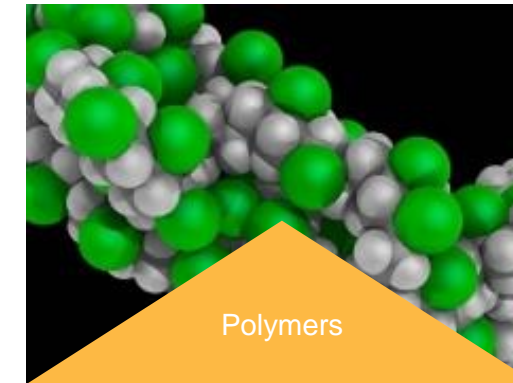
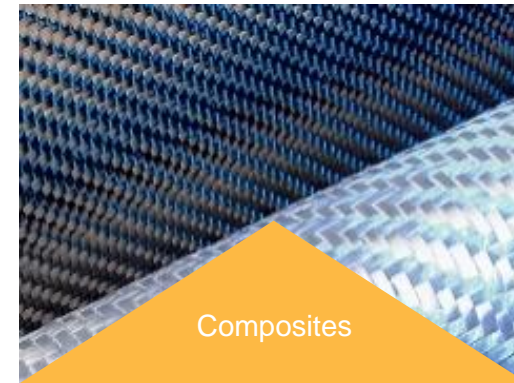
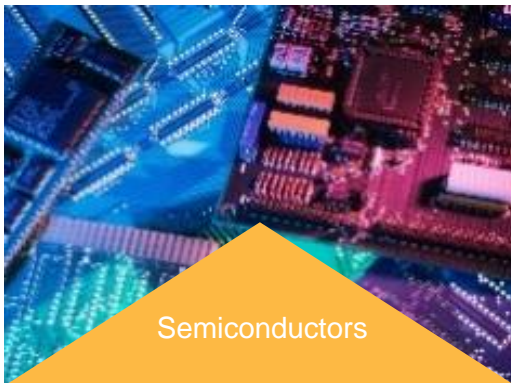
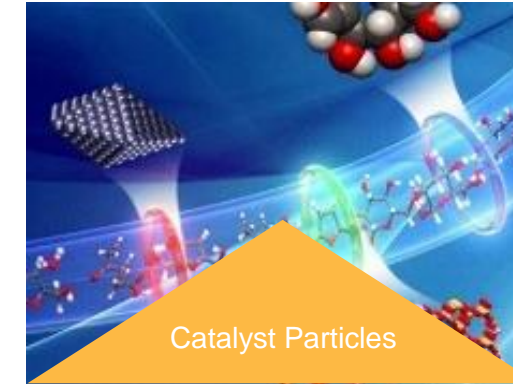
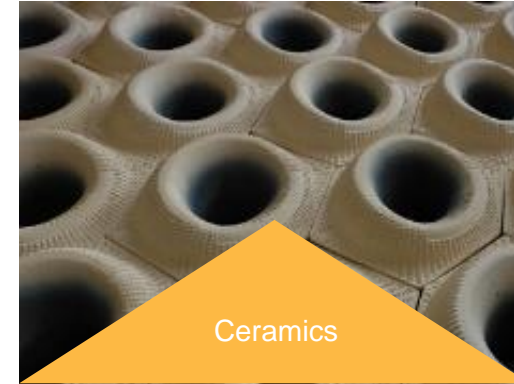
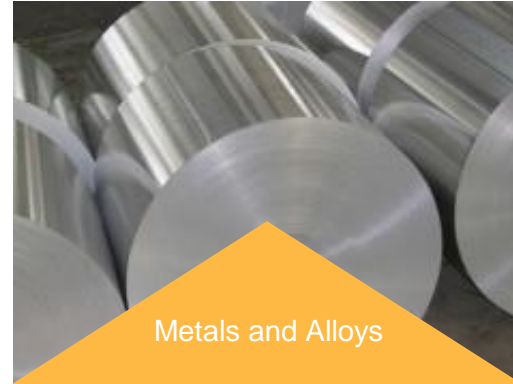
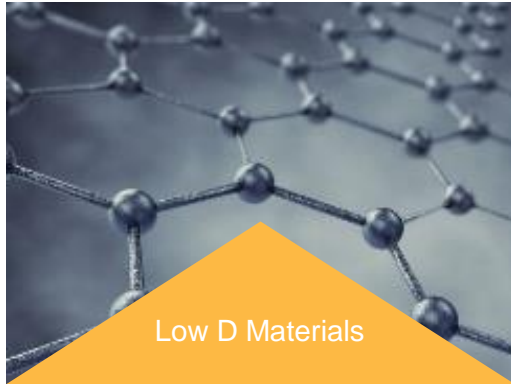


Conditions: FIB lamella, 140 – 200 °C, 20 hours, HAADF STEM

Results: Mechanism of the morphological evolution of the precipitates in Al alloys

Liu, Chunhui, et al. *Scientific reports* 7 (2017).

In situ heating applications



The new heating Nano-Chip



Optimized heater's dimensions and shape
Improved stability, temperature uniformity and IR emission

Optimized for sample handling
Largest viewable area and optimum design to safely handle the most common types of samples



> 850 μm^2
Viewable area



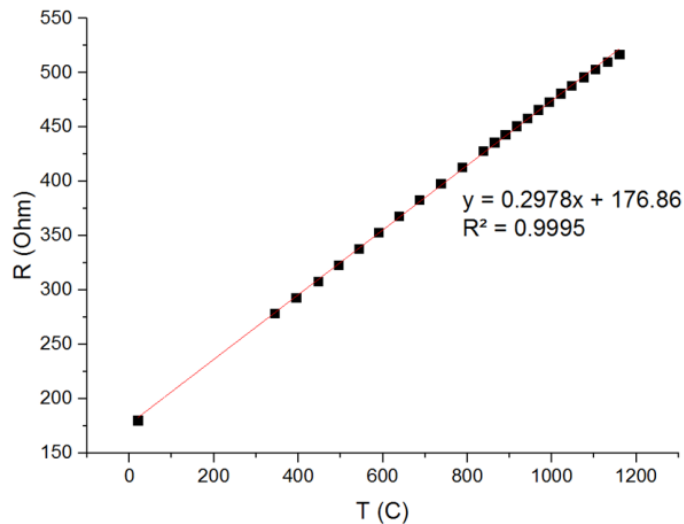
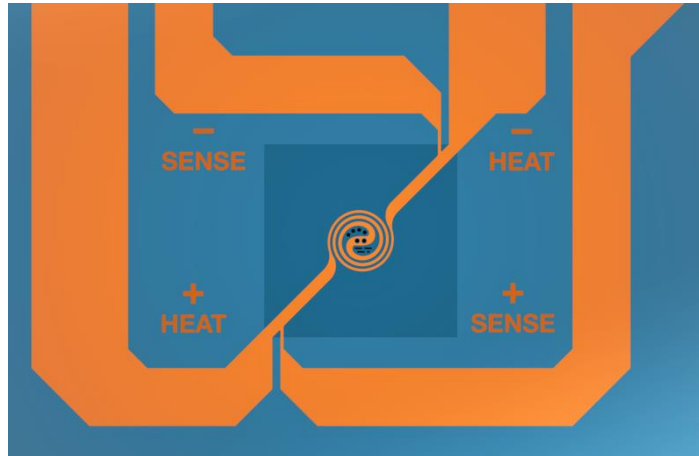
Optimized
for different samples



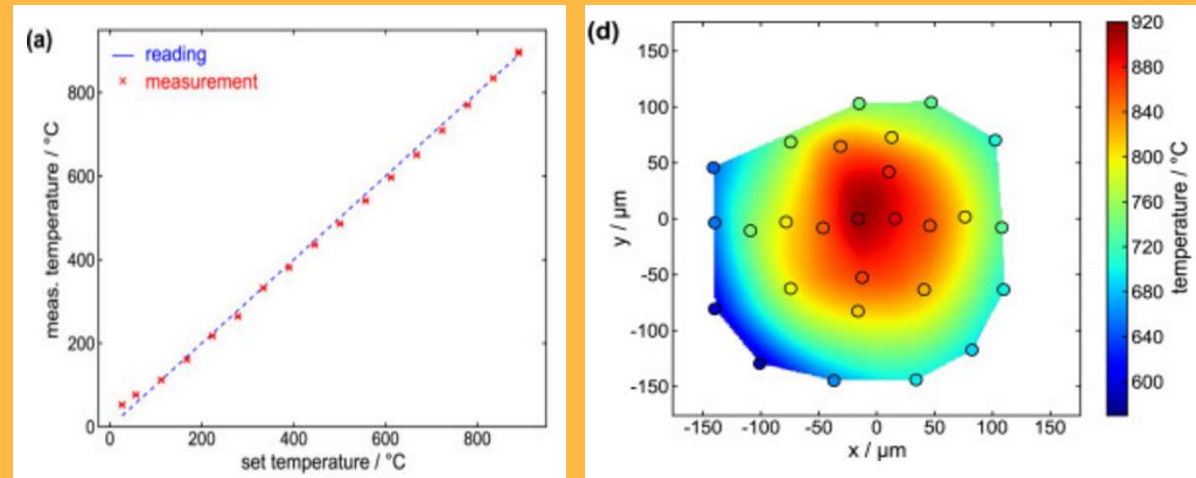
Increased
success rate

Results you trust

Local temperature measurements
Resistance as a temperature indicator

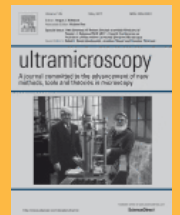


Temperature accuracy and homogeneity proven by customers by local measurements in TEM



The local sample temperature is measured in TEM by NB electron diffraction. Results indicate a high temperature uniformity with deviations around 3%.

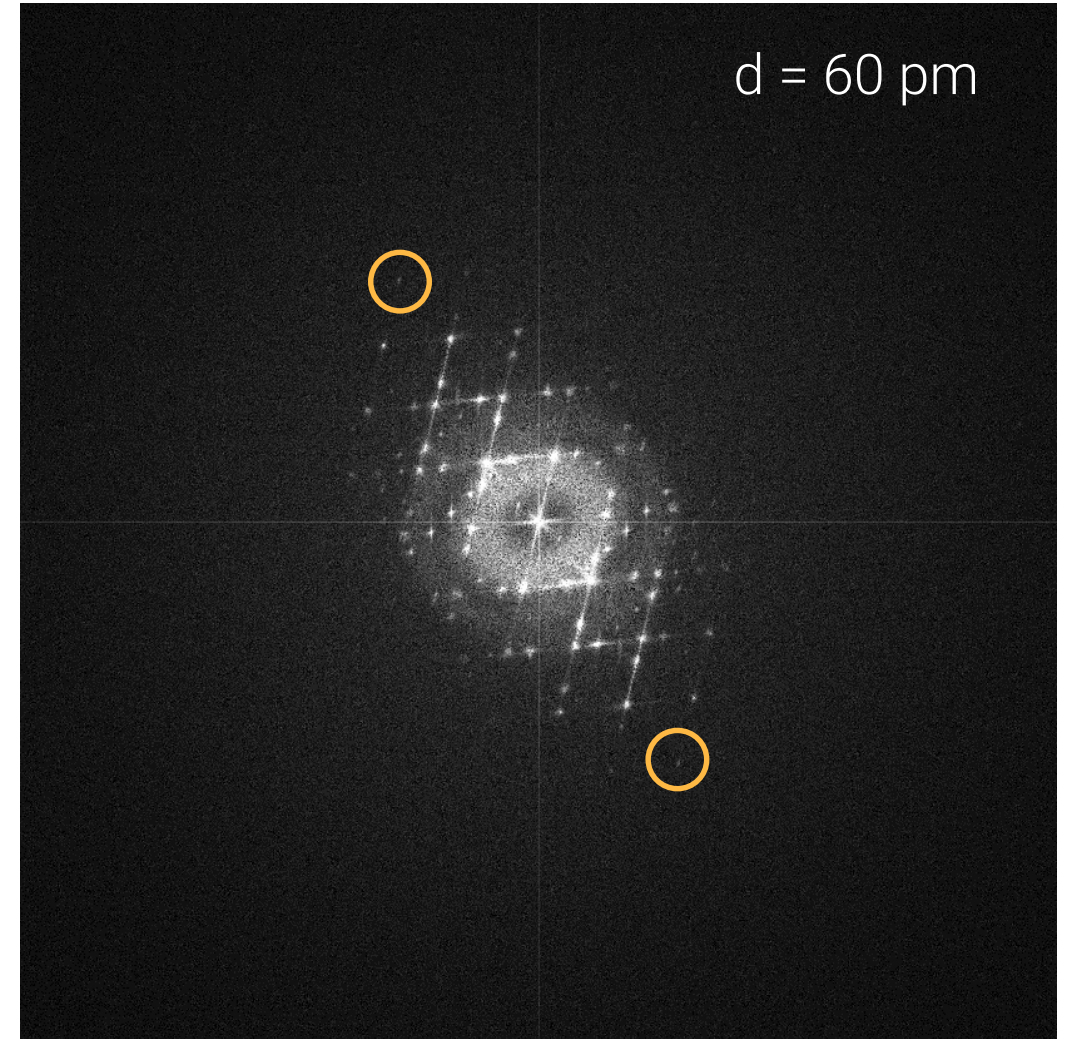
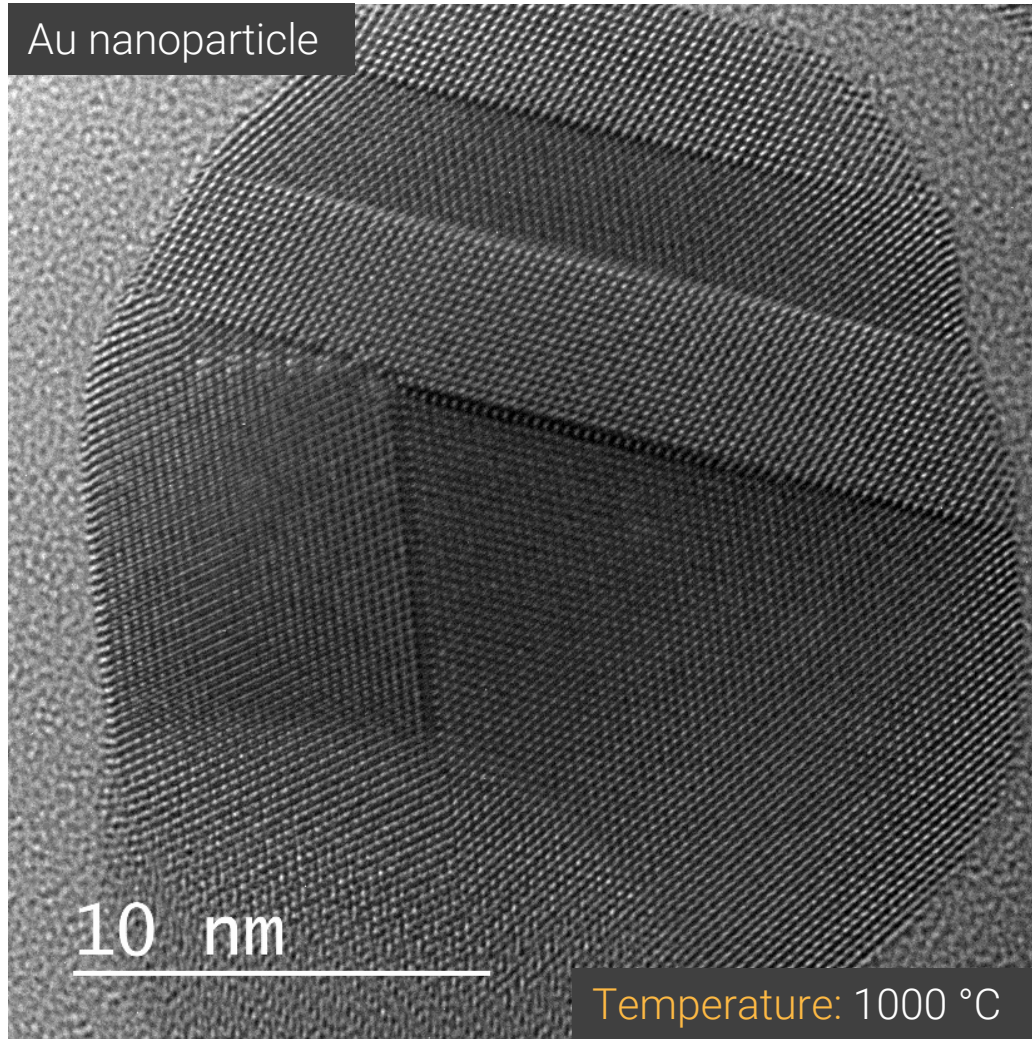
Florian Niekief, et al. Ultramicroscopy (2016).



Full S/TEM performance guaranteed

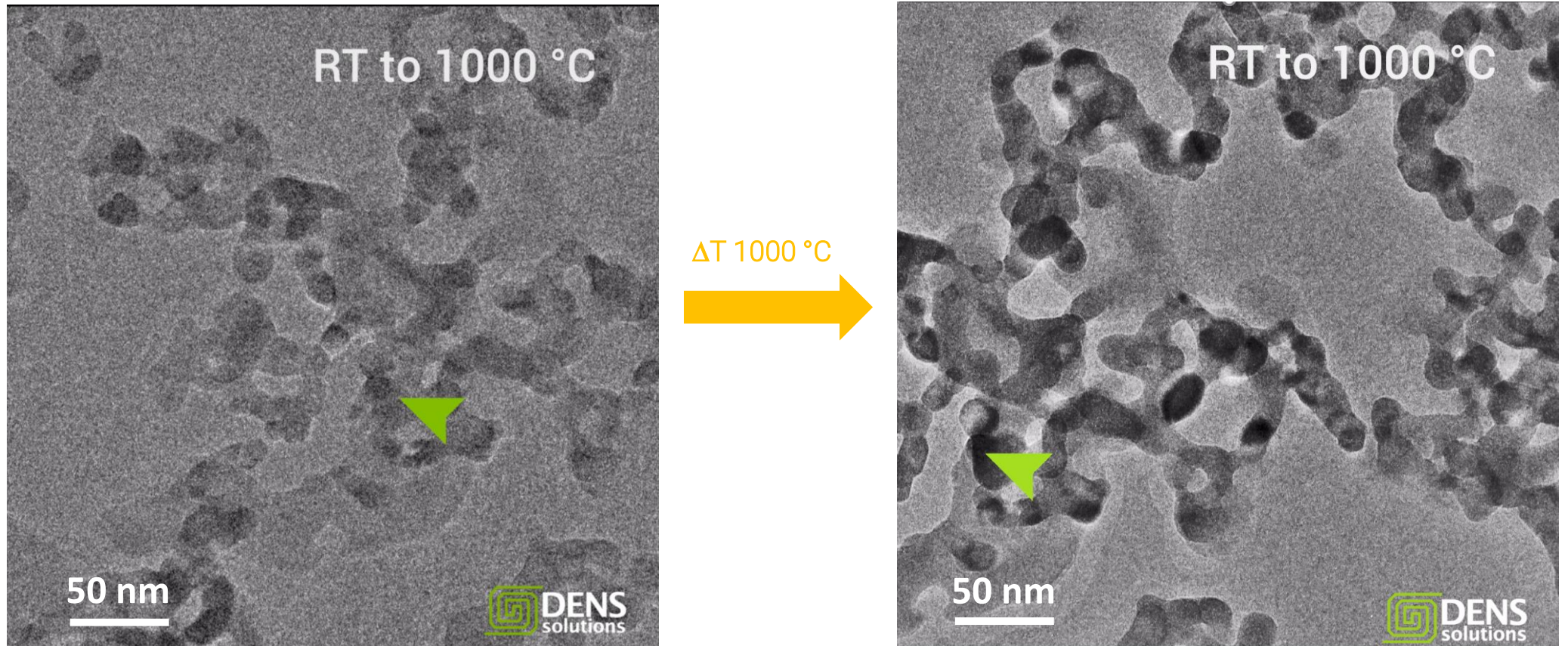
The best TEM performance in any environment

Au nanoparticle



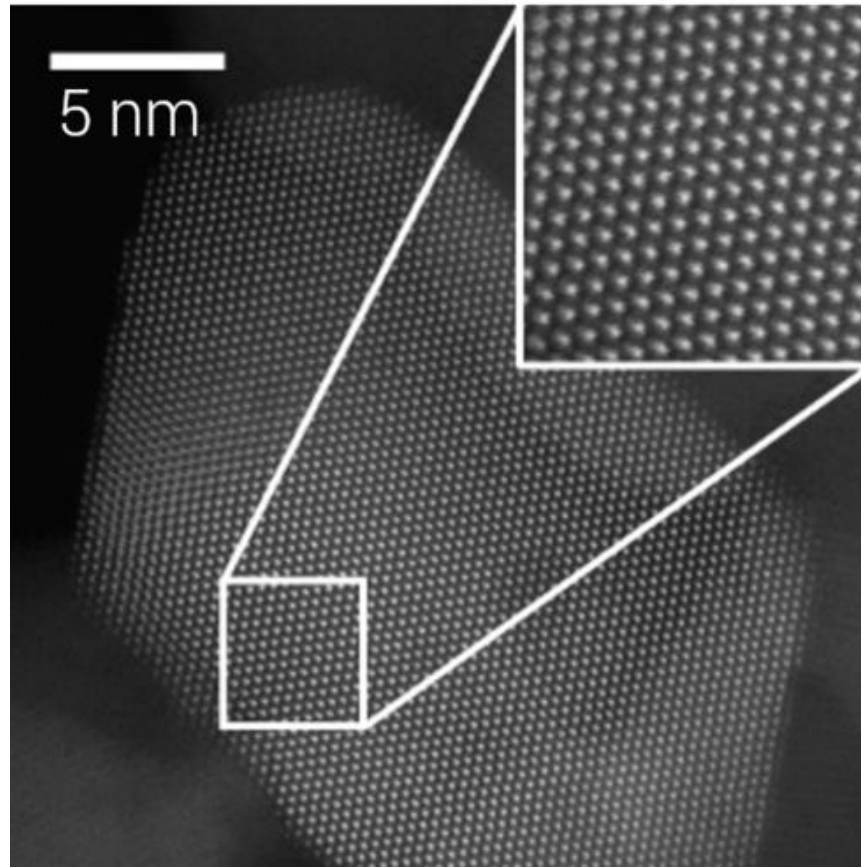
Never miss a thing

The highest sample stability in 3 dimensions

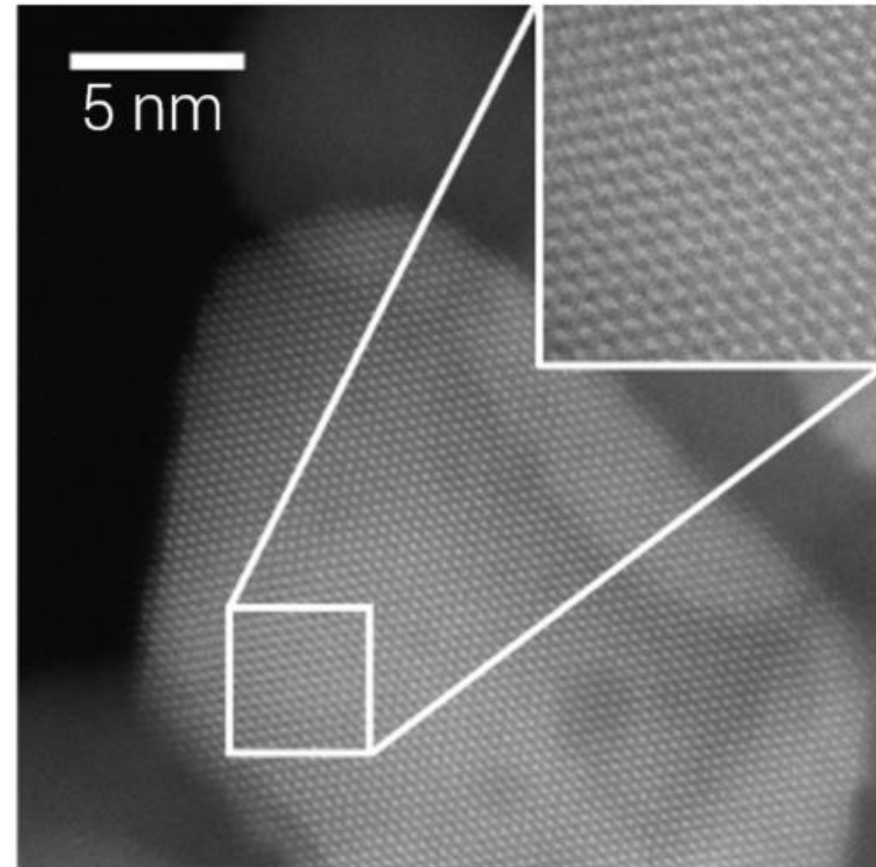


Less bulging: better resolution?

From RT to 750 °C, image refocused with FOCUS



NEW design



PREVIOUS design

Fast results with more impact

Impulse, the next-gen in situ SW

vw impulse



Features:

- Synchronized control of all in situ stimuli
- Graphical profile builder
- Fully customizable UI

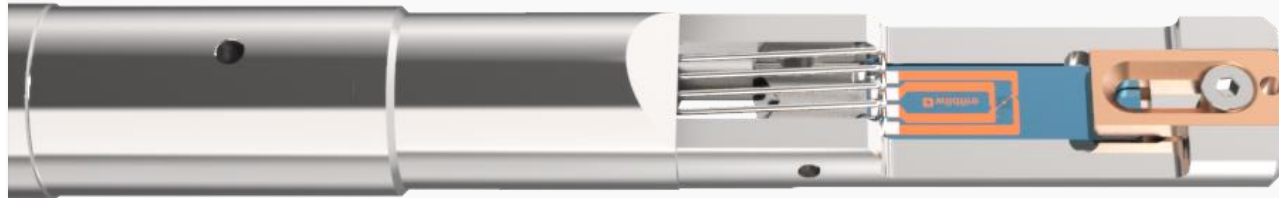
Benefits:

- Easily correlate all the in situ parameters
- Set up complex experiments with only few mouse clicks
- Monitor conveniently only the parameters that matter

The complete Wildfire range

Our products

Thermo Scientific TEM



Wildfire H	Wildfire H+	Wildfire H+ 3D	Wildfire H+ DT
RT – 600 °C	RT – 1300 °C	RT – 1300 °C	RT – 1300 °C
±30 ° alpha tilt	±30° alpha tilt	±70° alpha tilt	±25° alpha and beta tilt

The complete Wildfire range

Our products

JEOL TEM

Wildfire H

RT – 600 °C

±20° alpha tilt

Wildfire H+

RT – 1300 °C

±20° alpha tilt

Wildfire H+ DT

RT – 1300 °C

±20° alpha tilt
±15° beta tilt



Our products

Portfolio & focus

 **wildfire**



Heating

Materials
Science

 **lightning**



Biasing

Micro
Electronics

 **climate**



Gas

Chemistry



Liquid

Life&materials
Sciences



INNOVATIONS THAT MATTER

Thank you for your time

<http://denssolutions.com/events/imc19/>



Outline

- Demonstrate element mapping results at 1000° C for the first time
- Heating can cause sample drift and membrane bulging
- Infrared radiation disturbs X-ray detection
 - Effects of heat and IR-radiation on EDS signal detection:
noise effects and peak broadening
- Elemental maps of Au/Pd nanoparticles
- Autophase results: tracking phase transition

System parameters

EDS



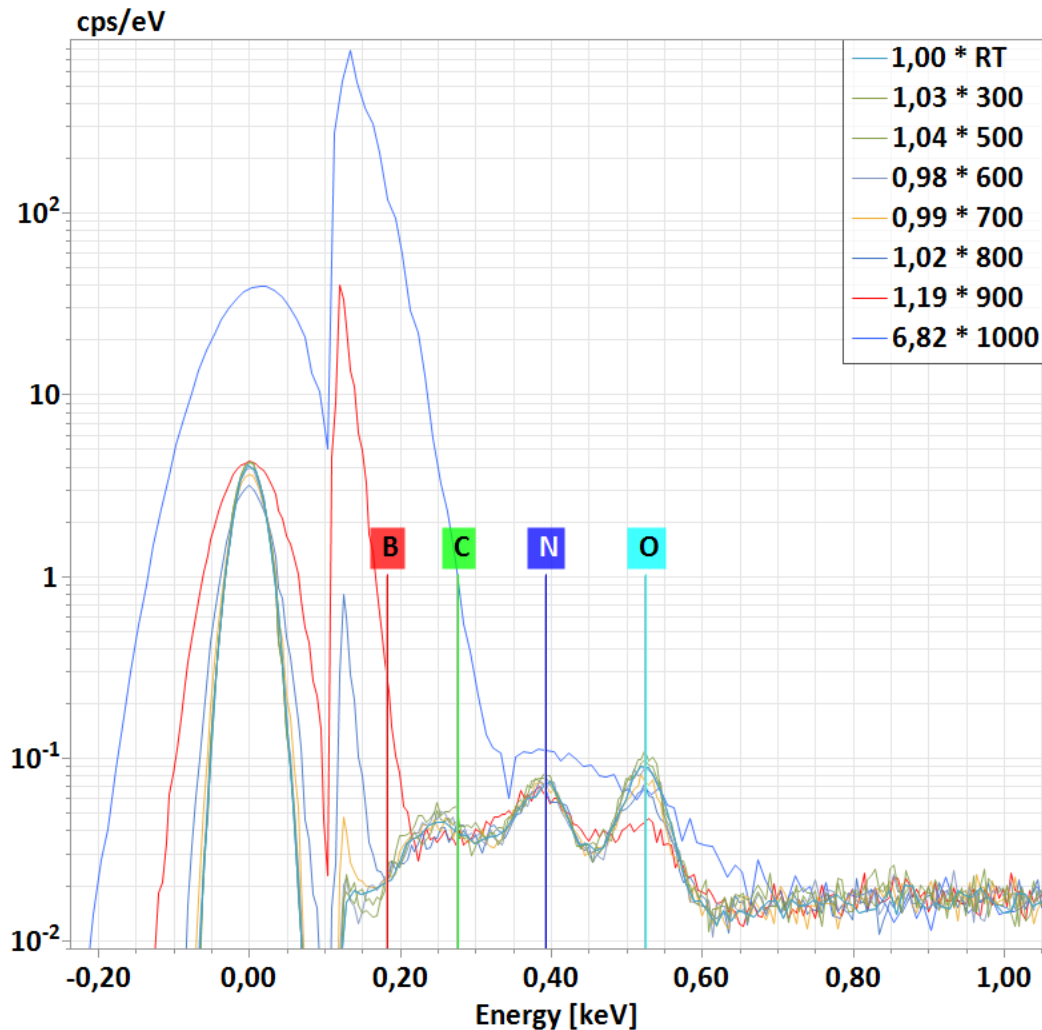
System configuration	
Microscope type	JEOL JEM-2200FS, UHR polepiece, operated at 200kV
Detector type	Bruker X-Flash® 5030T, 30mm ² active SDD chip size, 0.12 sr solid angle
SW configuration	Hypermap, drift correction, Autophase
SW options	online deconvolution – included in basic SW package
Sample holder	DENS Solutions, Wildfire in-situ heating sample holder

STEM located at the Humboldt University of Berlin, Institute of Physics

We thank **Dr. Holm Kirmse** (HUB) for operating the STEM and

Sander van Weperen (DENSsolutions) for operating the Wildfire system!

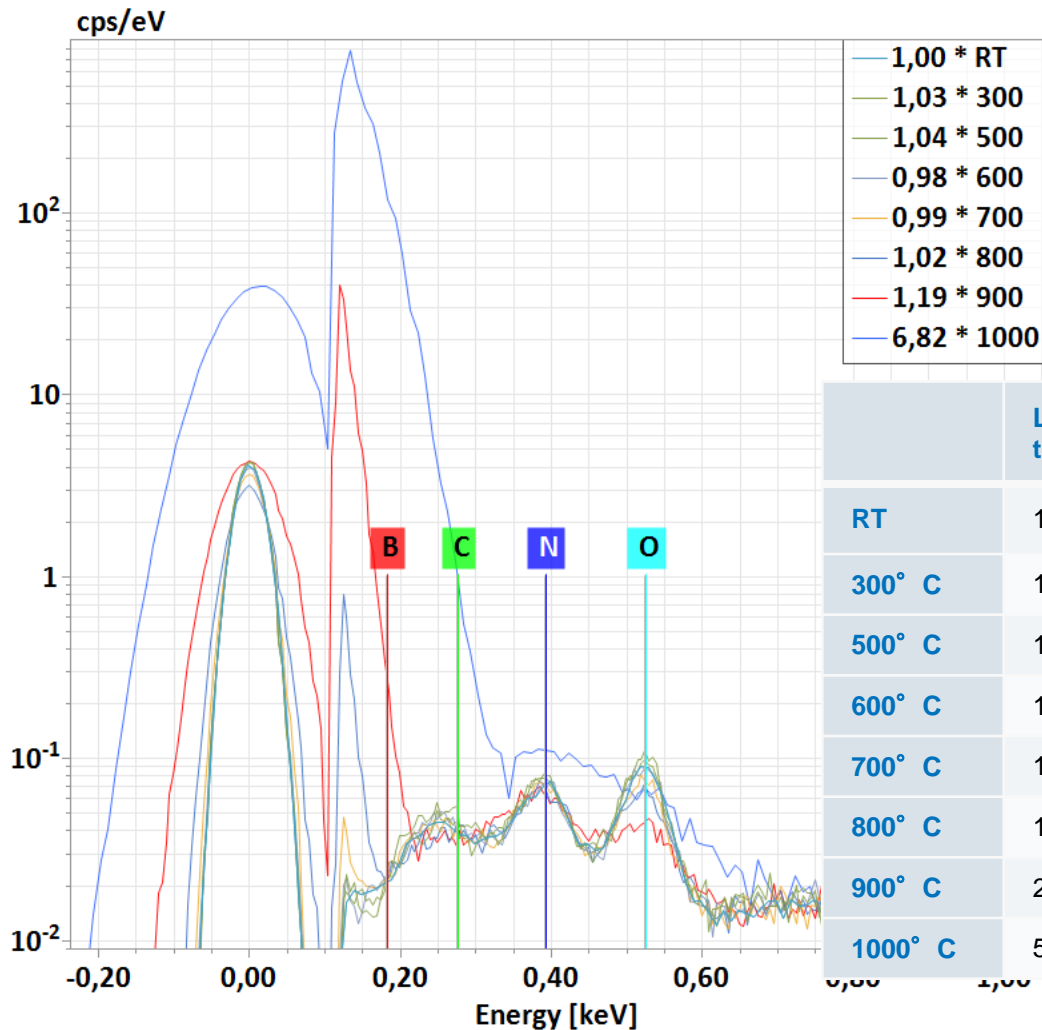
IR-radiation and heating affecting SDD



Effect of infrared radiation for X-ray detection with an SDD:

- **Noise effects:** the low energy region: detection of low kV X-rays is disturbed. Rising noise at low energies. -> low energy threshold for useful data interpretation
- **Peak broadening:** peak FWHM is increasing.

IR-radiation effect – low energy threshold



Low energy threshold: the minimal energy for useful data interpretation

	Low energy threshold	Si K-peak FWHM	Pd L α - peak FWHM	Au L α - peak FWHM
RT	110 eV	79,4 eV	88,3 eV	169,2 eV
300° C	110 eV	80,6 eV	84,4 eV	167,6 eV
500° C	110 eV	79,6 eV	83,5 eV	167,7 eV
600° C	110 eV	79,6 eV	86,3 eV	168,1 eV
700° C	150 eV	82,5 eV	89,4 eV	169,3 eV
800° C	180 eV	91,3 eV	92,9 eV	172,0 eV
900° C	215 eV	110,6 eV	111,9 eV	188,7 eV
1000° C	500 eV	148,5 eV	182,4 eV	219,6 eV

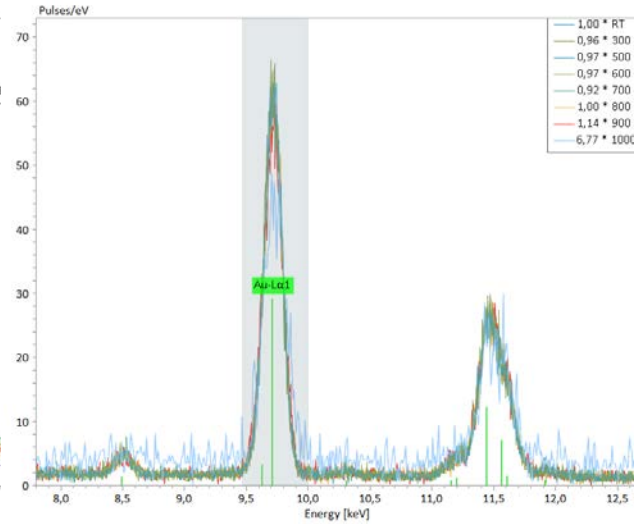
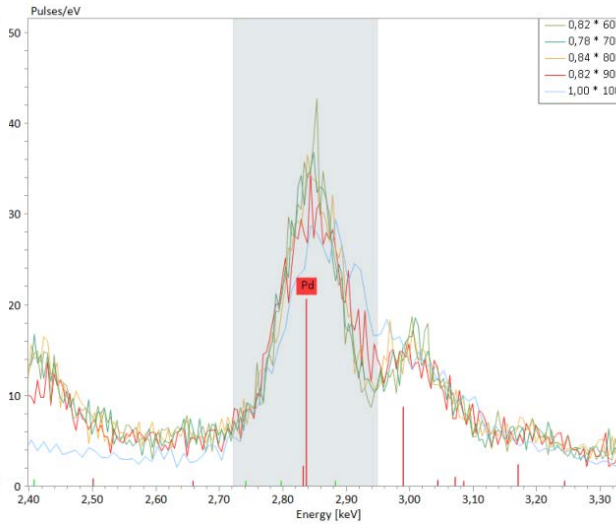
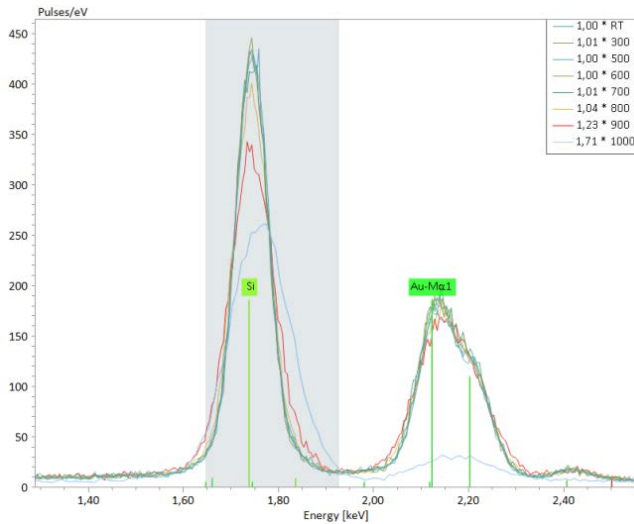
IR-radiation effect – peak broadening



Si K α (1,740 keV)

Pd L α (2,837 keV)

Au L α (9,704 keV)



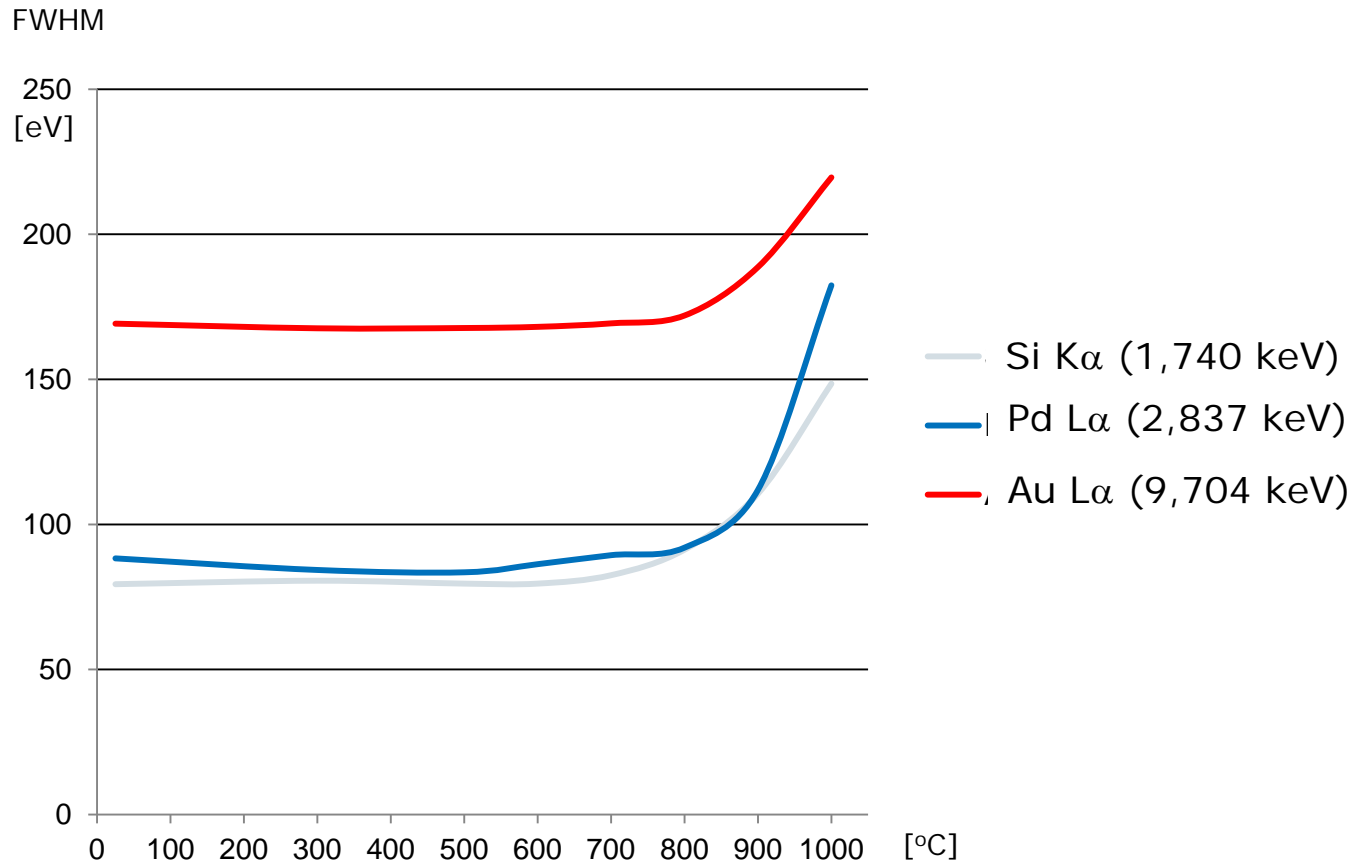
EDS	FWHM [eV]
EDS RT	79,4
EDS 300	80,6
EDS 500	79,6
EDS 600	79,6
EDS 700	82,5
EDS 800	91,3
EDS 900	110,6
EDS 1000	148,5

EDS	FWHM [eV]
EDS RT	88,3
EDS 300	84,4
EDS 500	83,5
EDS 600	86,3
EDS 700	89,4
EDS 800	92,0
EDS 900	111,9
EDS 1000	182,4

EDS	FWHM [eV]
EDS RT	169,2
EDS 300	167,6
EDS 500	167,7
EDS 600	168,1
EDS 700	169,3
EDS 800	172,0
EDS 900	188,7
EDS 1000	219,6

- Stronger peak broadening at lower energies
- Peaks are still significantly strong to use EDX signal for element mapping

IR-radiation effect – peak broadening



- Stronger peak broadening at lower energies
- Peaks are still significantly strong to use EDX signal for element mapping

Sample



Au/Pd sputtered on a silicon-nitride membrane.

Nominal layer thickness: 10nm

The Au/Pd material system is a good model system to demonstrate processes like

- dewetting, **element segregation** within nanoparticles
- nanoparticle **size and shape change**
- **evaporation of elements** (Au) due to melting temperature differences

Measurement parameters

EDS and STEM



Measurement parameters	
Map size	256 x 246 pixels
Pixel size	0.55 nm
Mapping time	15 minutes
Input count rate	220-260 cps
Drift correction	active

STEM-EDS geometry parameters	
Take off angle	22°
Solid angle	0.12 sr
Sample tilt	0°
Beam current	350pA
SDD window	Super Light Element Window (SLEW) AP3.3 (Moxtek)

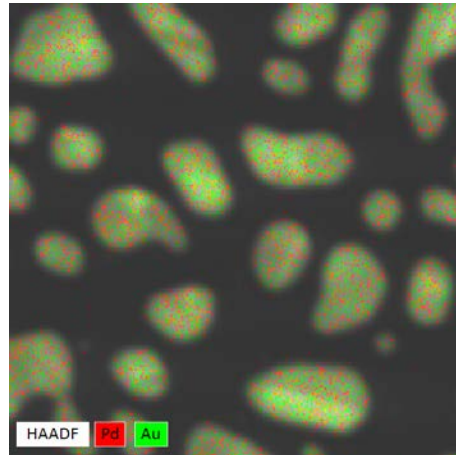
Mapping at different temperatures



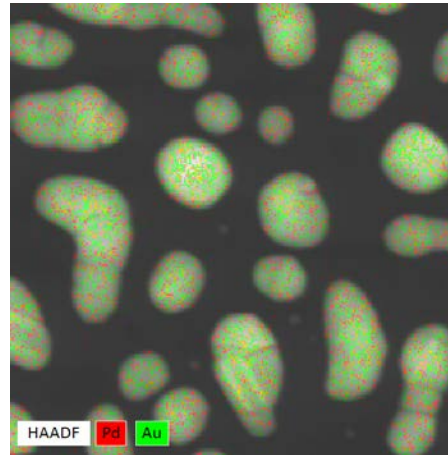
RT, 500, 600° C:
random sample areas

700-1000° C:
same sample area

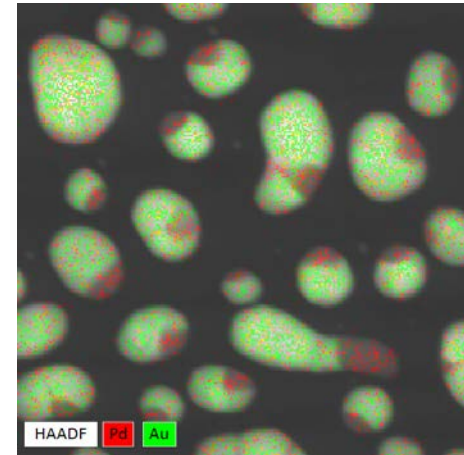
RT



500° C



600° C

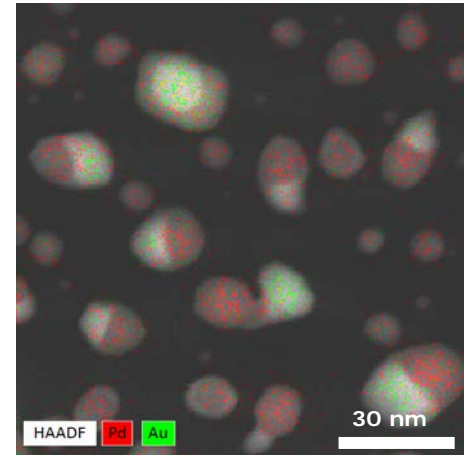
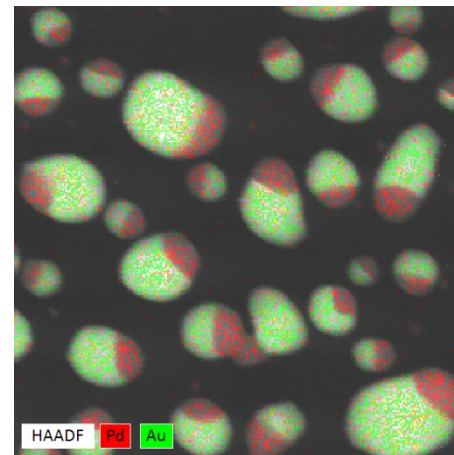
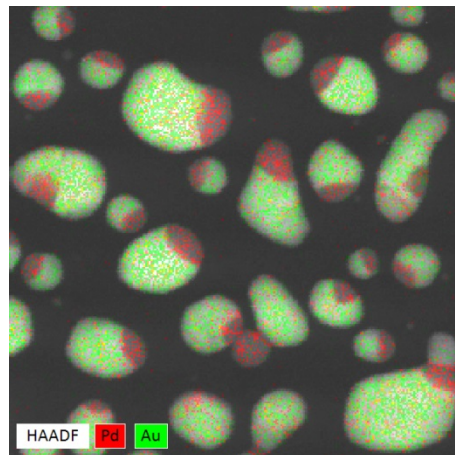
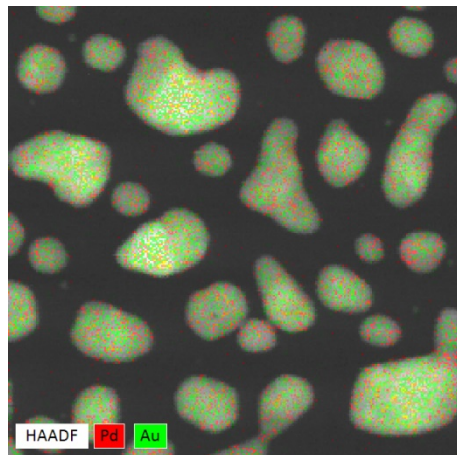


700° C

800° C

900° C

1000° C

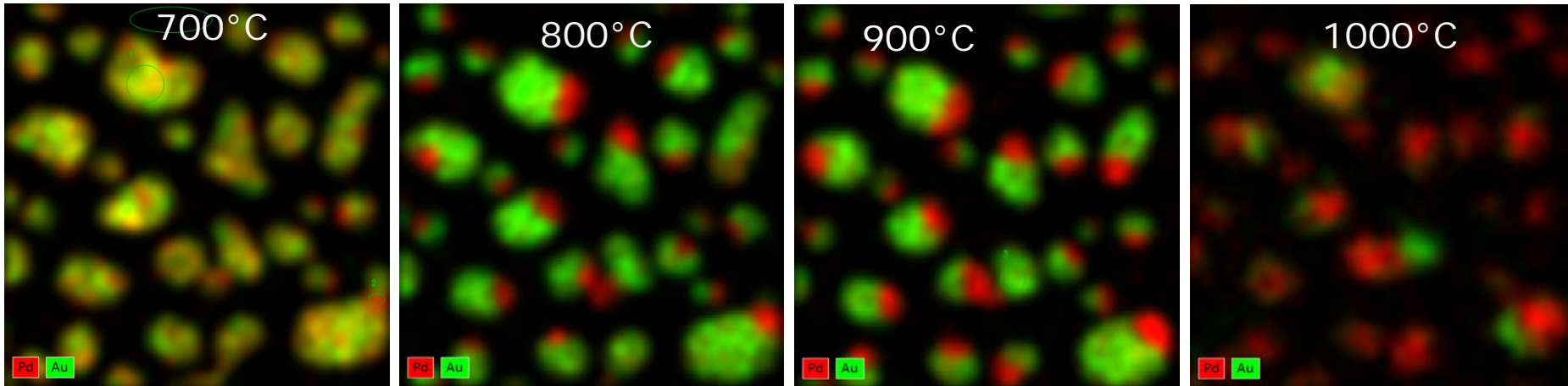


Maps with autofilter

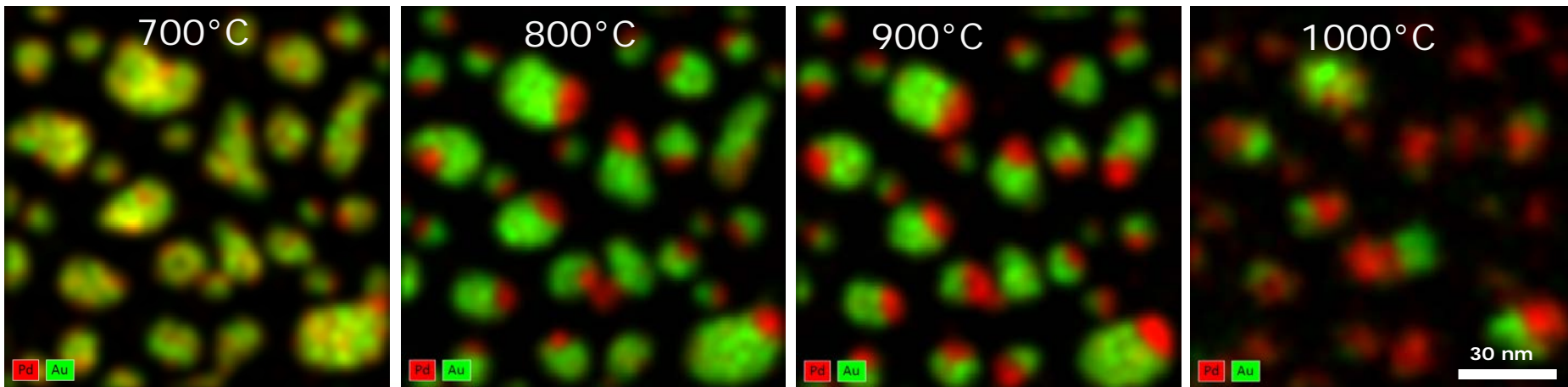
Au M-lines (2,123kV) & Au L-lines (9,704kV)



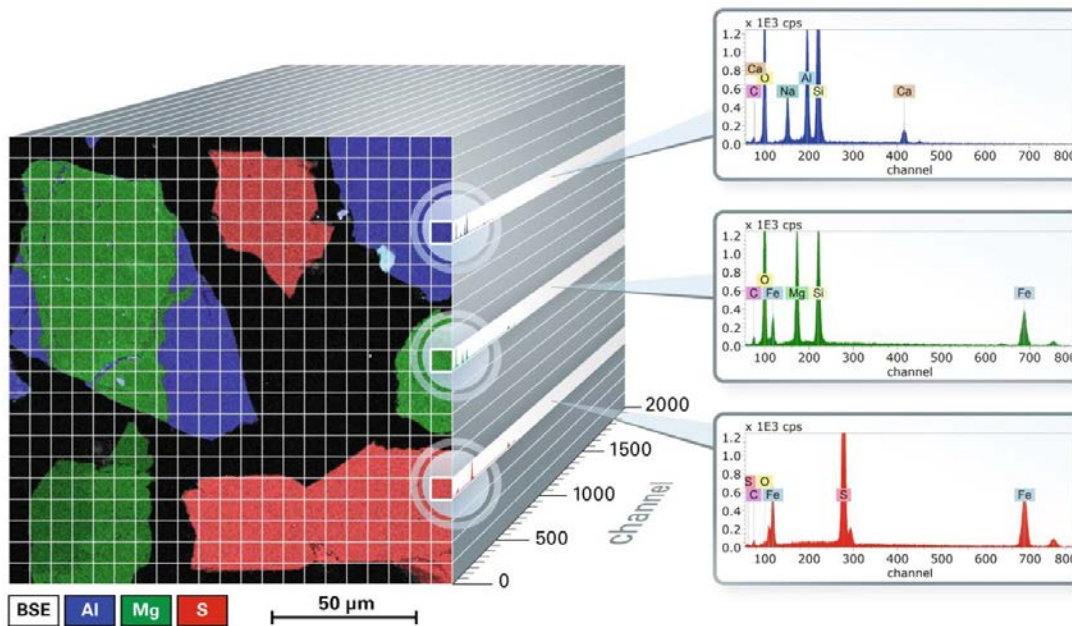
Au L-lines



Au M-lines



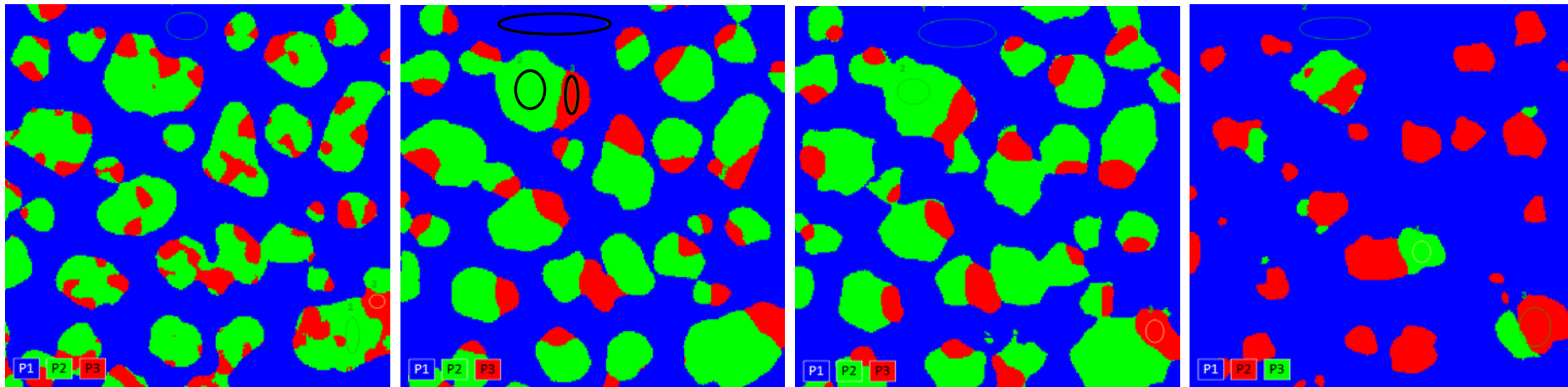
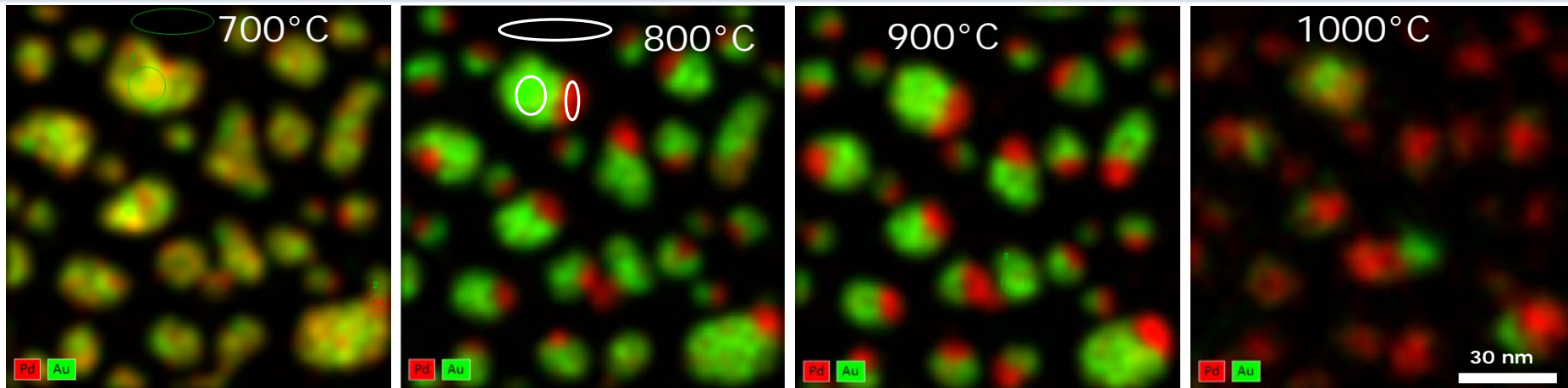
Autophase – find „similar“ areas in a map



Autophase workflow:

All spectra in a Hypermap can be described with as an n-dimensional data vector. Autophase uses different algorithms (like PCA) to identify and sort “similar” spectra within the map.

Autophase results



	Counts/Pixel	Area
■ P1		59,2 %
■ P2	Au	30,5 %
■ P3	Pd	10,3 %

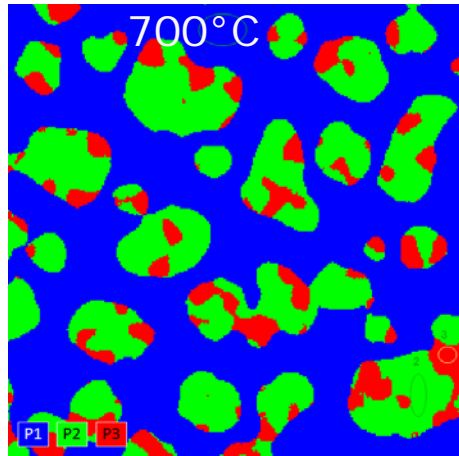
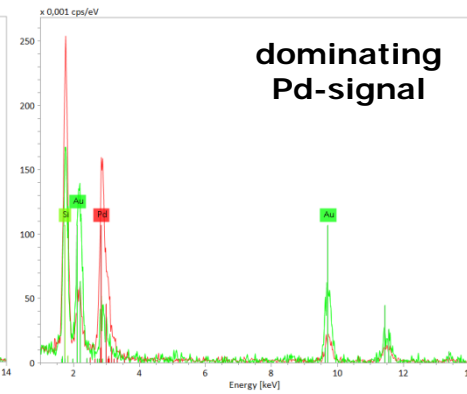
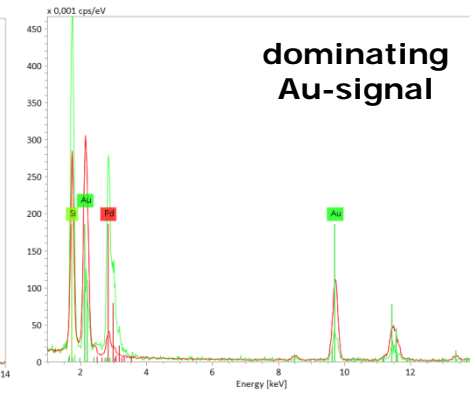
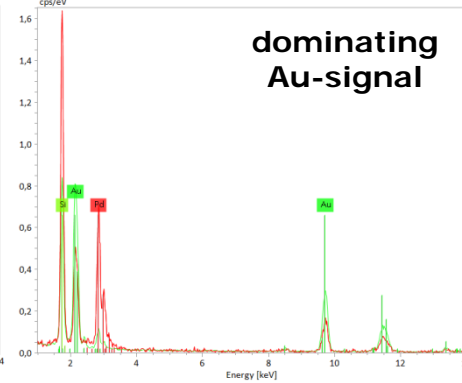
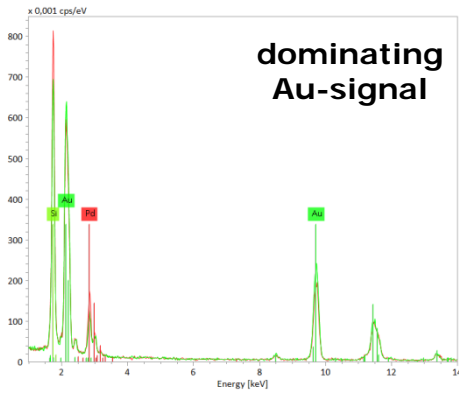
	Counts/Pixel	Area
■ P1		58,1 %
■ P2	Au	32,2 %
■ P3	Pd	9,7 %

	Counts/Pixel	Area
■ P1		57,1 %
■ P2	Au	33,6 %
■ P3	Pd	9,3 %

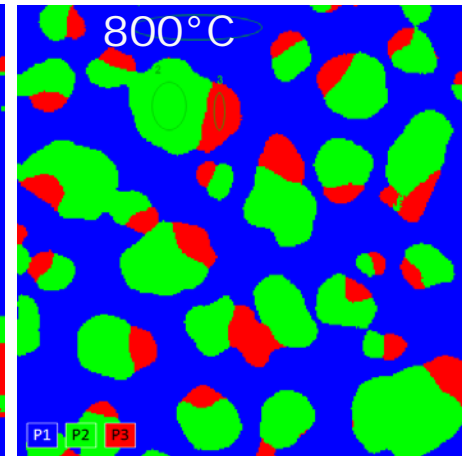
	Counts/Pixel	Area
■ P1		82,6 %
■ P3	Pd	13,8 %
■ P2	Au	3,7 %

Autophase results

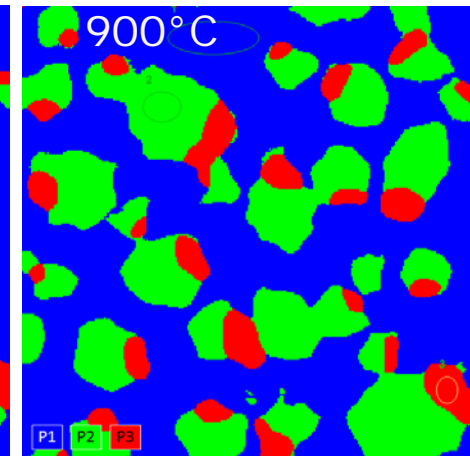
Phase changes



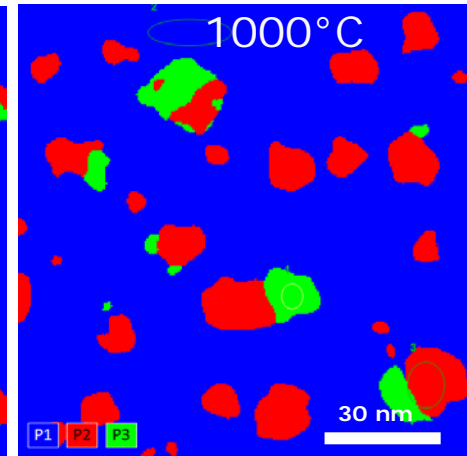
	Counts/Pixel	Area
■ P1		59,2 %
■ P2	Au	30,5 %
■ P3	Pd	10,3 %



	Counts/Pixel	Area
■ P1		58,1 %
■ P2	Au	32,2 %
■ P3	Pd	9,7 %



	Counts/Pixel	Area
■ P1		57,1 %
■ P2	Au	33,6 %
■ P3	Pd	9,3 %



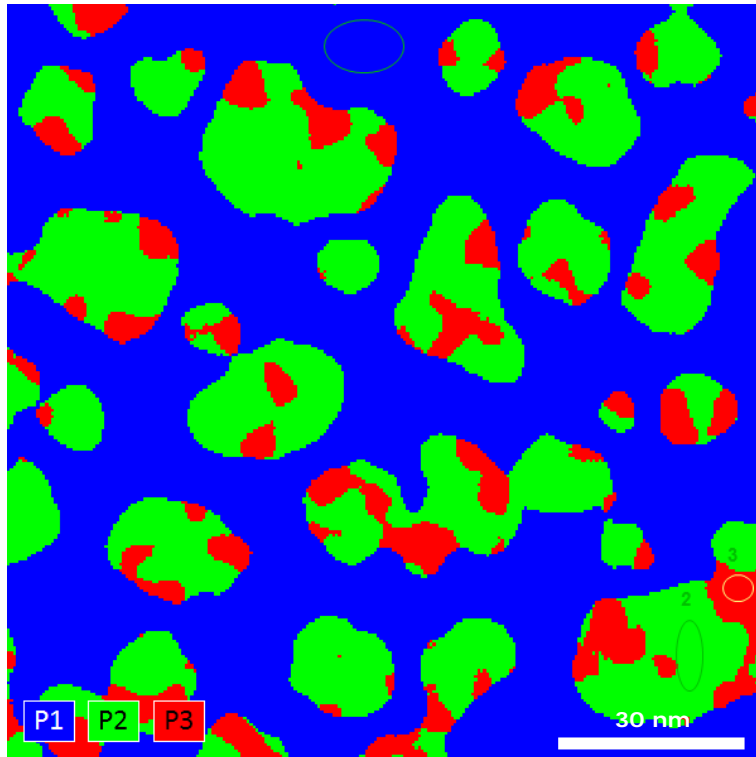
	Counts/Pixel	Area
■ P1		82,6 %
■ P3	Pd	13,8 %
■ P2	Au	3,7 %

Autophase results

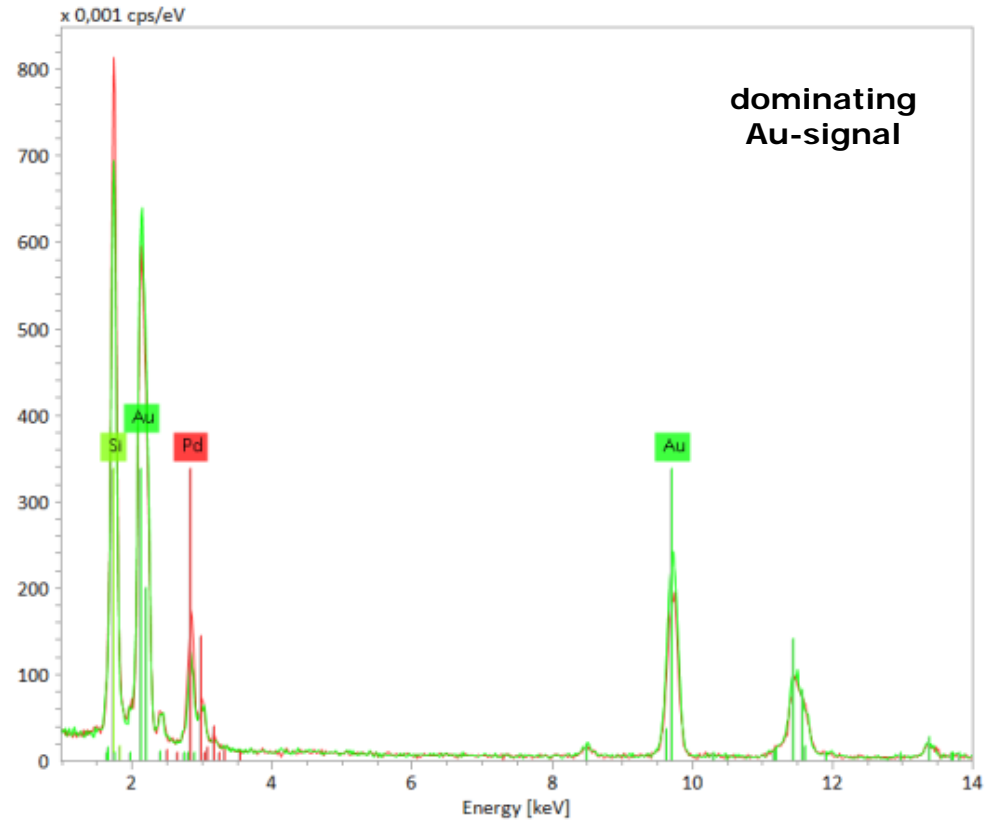
Phase changes



700°C



	Counts/Pixel	Area
P1		59,2 %
P2	Au	30,5 %
P3	Pd	10,3 %

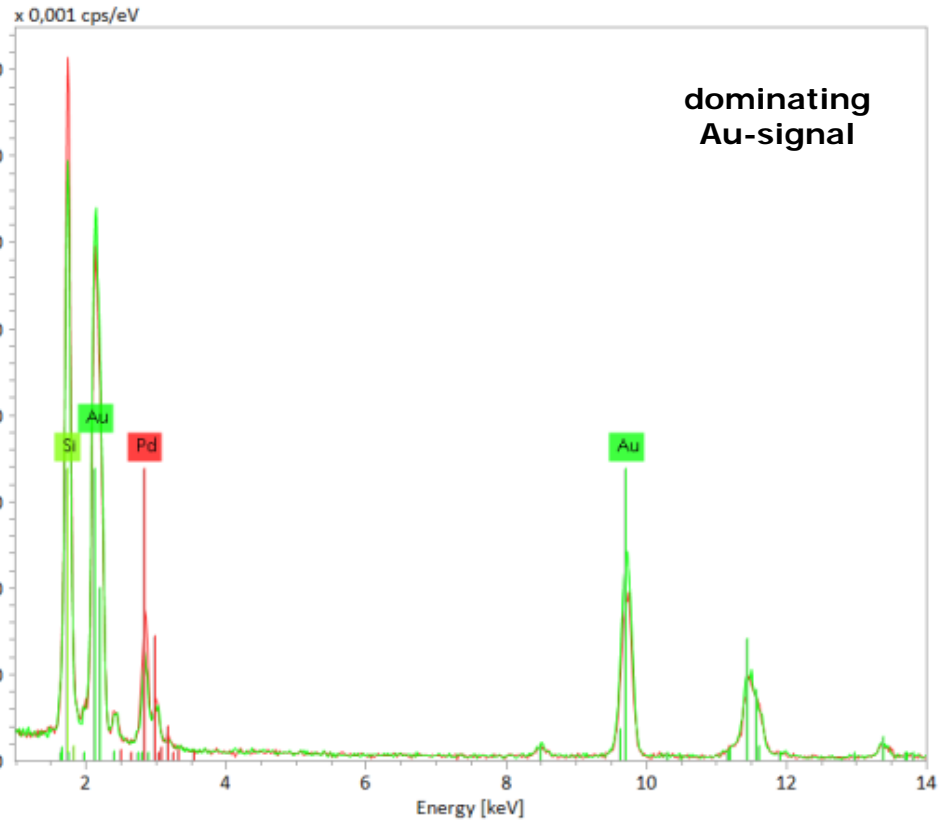
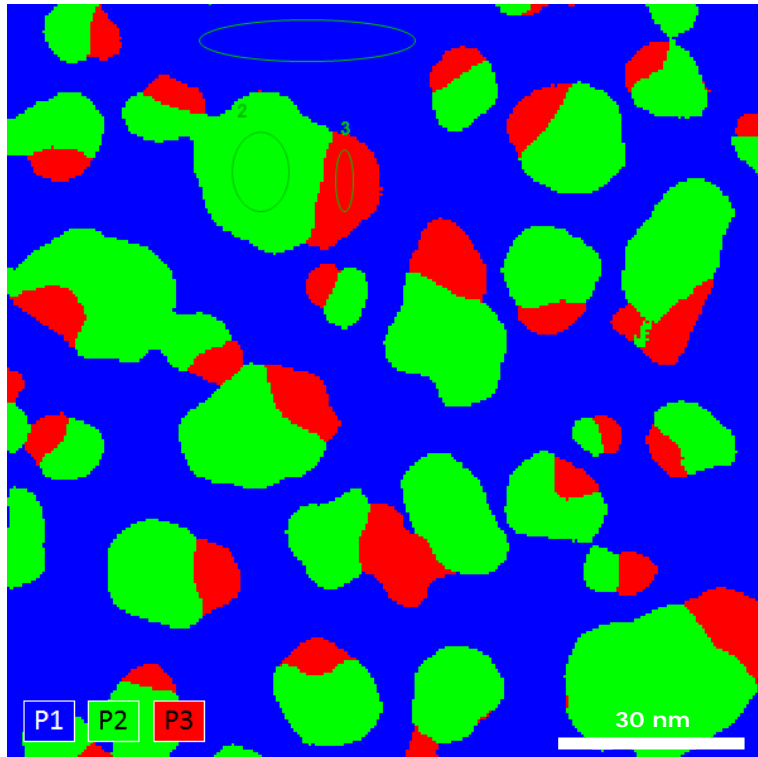


Autophase results

Phase changes



800°C



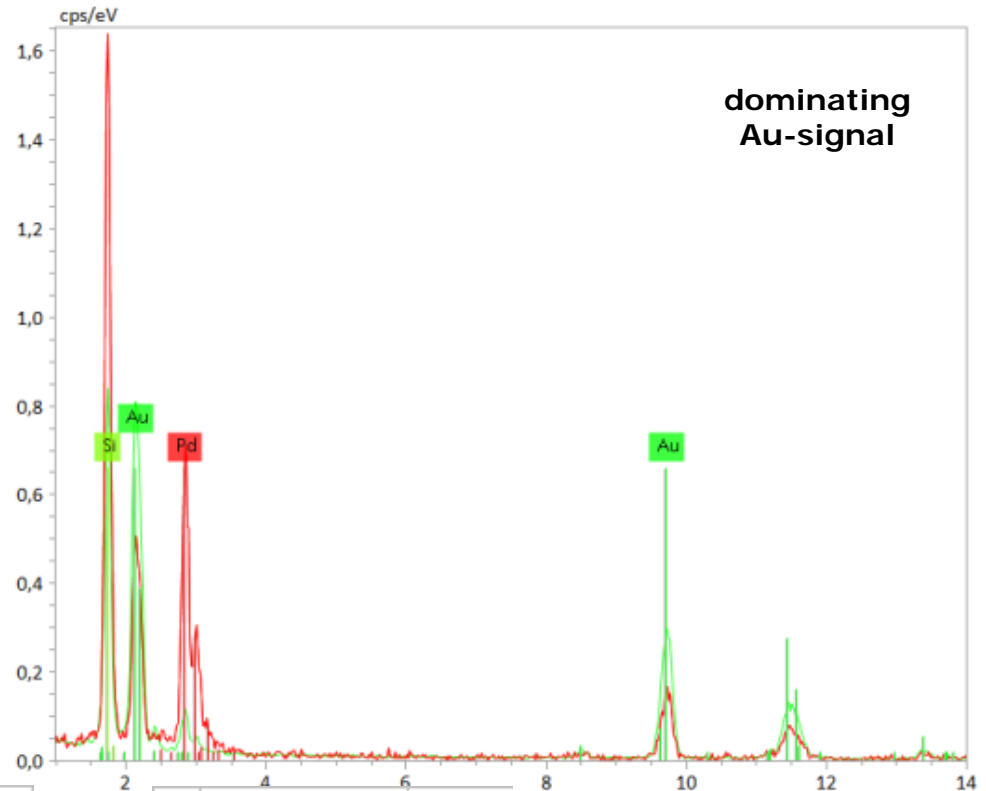
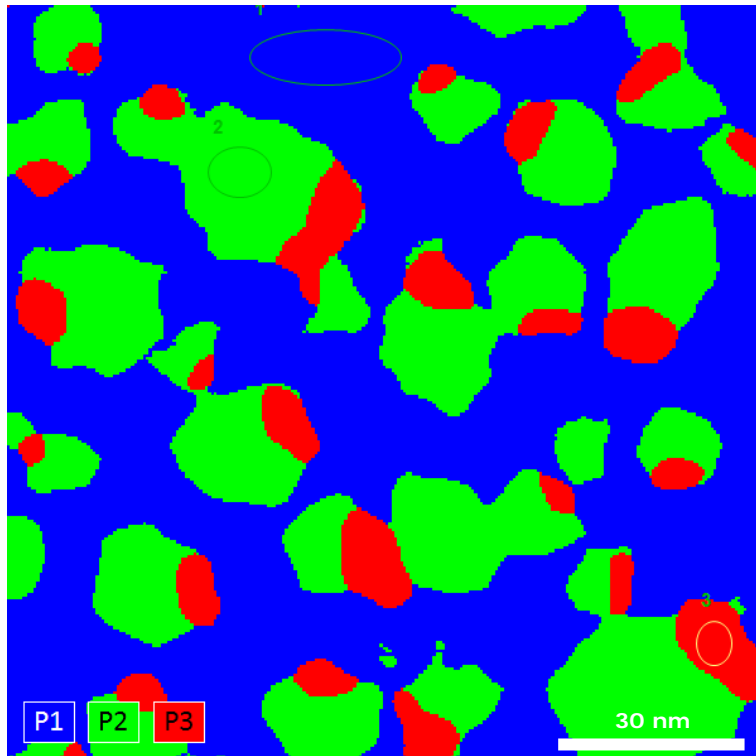
	Counts/Pixel	Area		Counts/Pixel	Area	
■	P1	59,2 %	→	■	P1	58,1 %
■	P2	Au 30,5 %		■	P2	Au 32,2 %
■	P3	Pd 10,3 %		■	P3	Pd 9,7 %

Autophase results

Phase changes



900°C



	Counts/Pixel	Area
■ P1		59,2 %
■ P2	Au	30,5 %
■ P3	Pd	10,3 %



	Counts/Pixel	Area
■ P1		58,1 %
■ P2	Au	32,2 %
■ P3	Pd	9,7 %



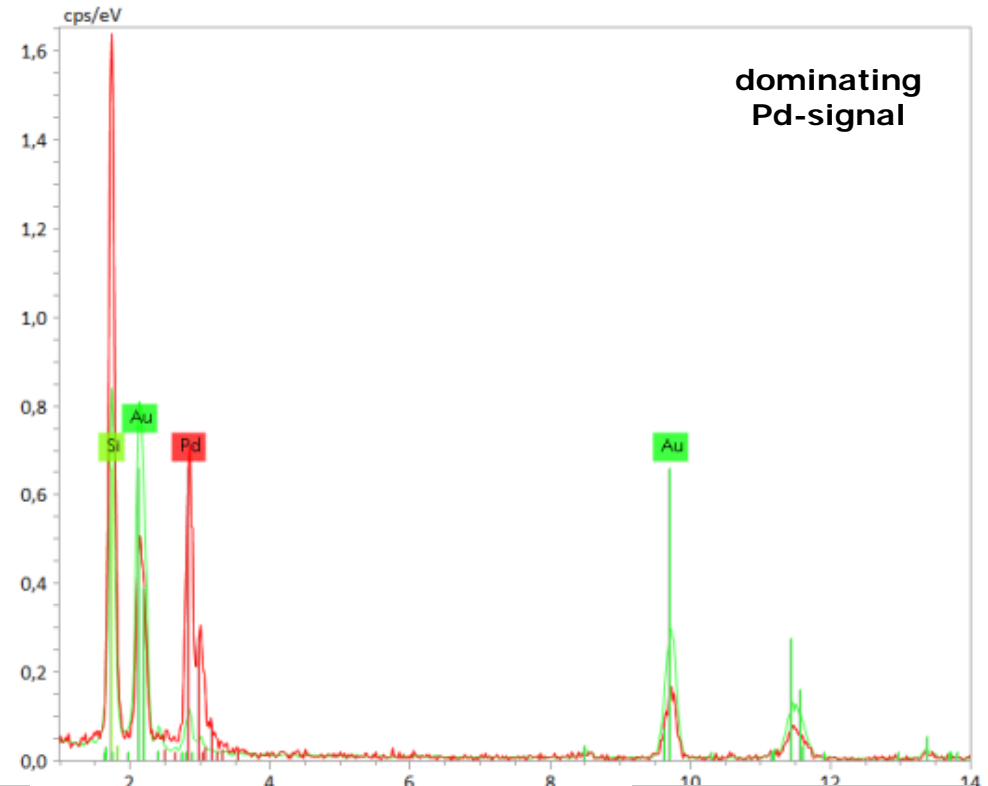
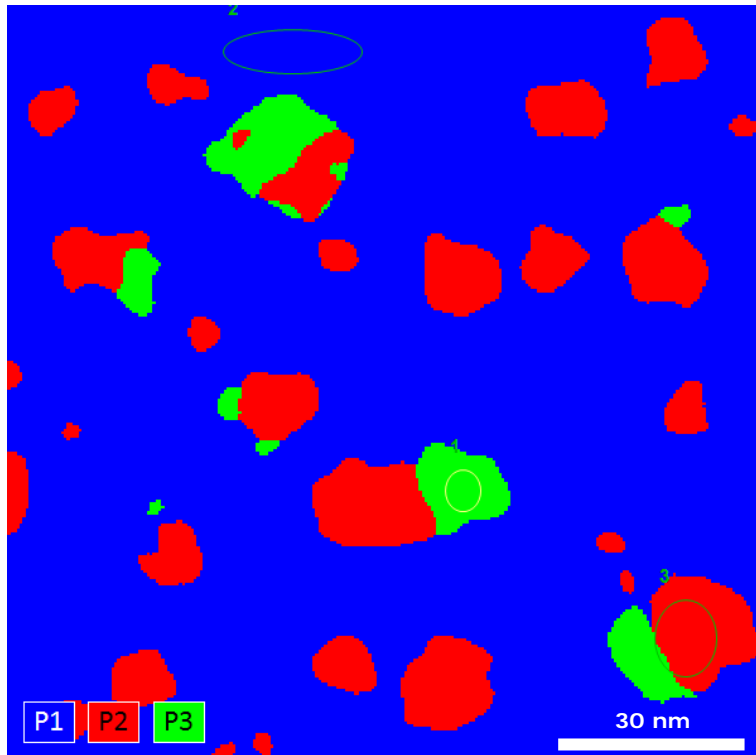
	Counts/Pixel	Area [keV]
■ P1		57,1 %
■ P2	Au	33,6 %
■ P3	Pd	9,3 %

Autophase results

Phase changes



1000°C



	Counts/Pixel	Area
■ P1		59,2 %
■ P2	Au	30,5 %
■ P3	Pd	10,3 %



	Counts/Pixel	Area
■ P1		58,1 %
■ P2	Au	32,2 %
■ P3	Pd	9,7 %



	Counts/Pixel	Area γ [keV]
■ P1		57,1 %
■ P2	Au	33,6 %
■ P3	Pd	9,3 %



	Counts/Pixel	Area
■ P1		82,6 %
■ P3	Pd	13,8 %
■ P2	Au	3,7 %

Autophase results

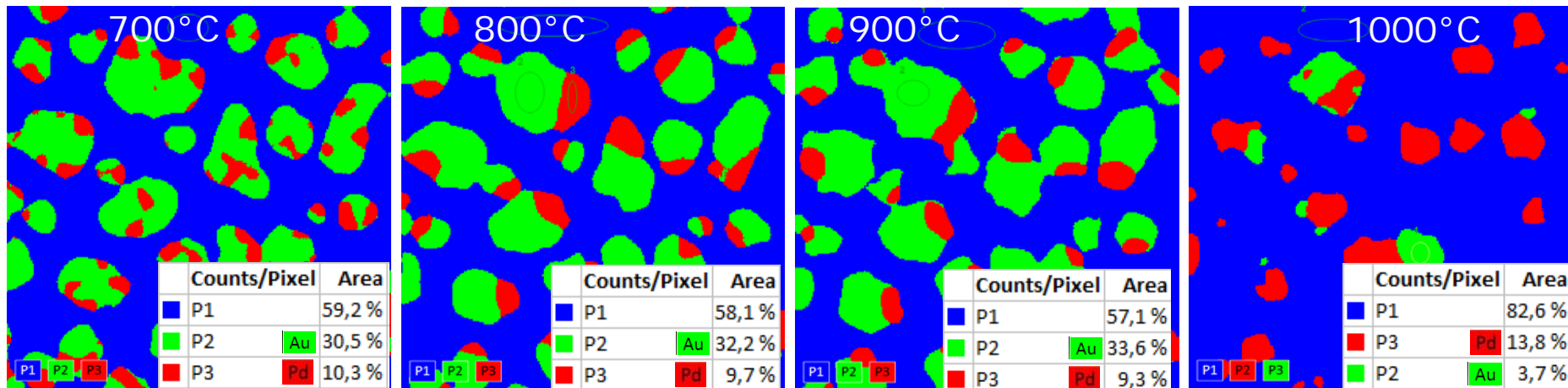
Phase changes



Au/Pd material system undergoes changes with increasing temperature:

- Ostwald ripening
- element segregation within nanoparticles: Au and Pd segregation
- shrinking of nanoparticles (material loss: individual particles decreasing)
- evaporation of elements (Au) due to melting temperature differences
- area coverage of Au is decreasing with increasing temperature

= > quantitatively measured using AutoPhase



Conclusions



- Demonstration and control of IR effect on EDS spectra using optimized in-situ sample holder
- Unprecedented in-situ heating study in STEM at temperatures up to 1000° C
- Esprit HyperMap and AutoPhase tool tracks phase transition of Au/Pt nanoparticles by measuring phase area coverage

Further information:

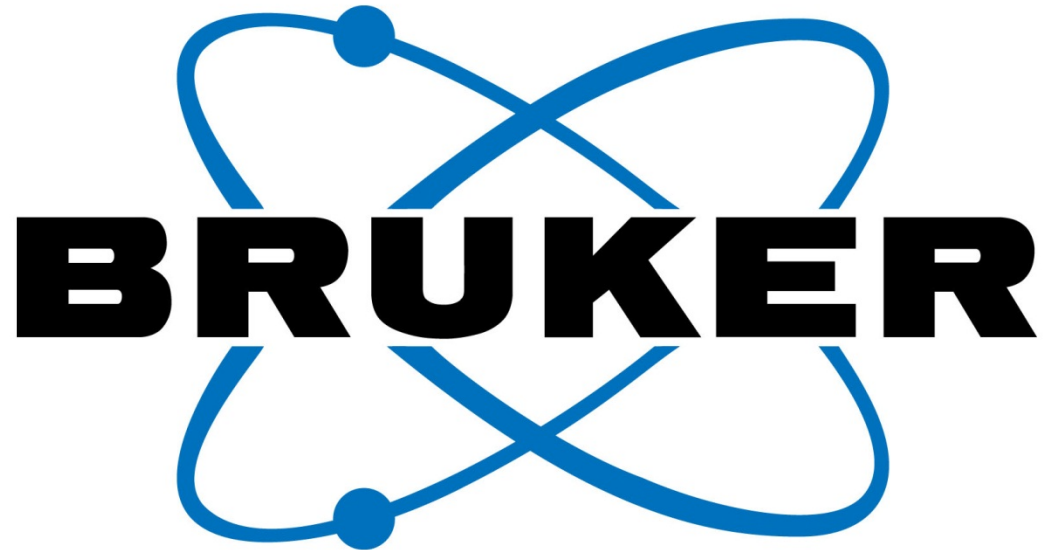
Advanced microheater for *in situ* transmission electron microscopy; enabling unexplored analytical studies and extreme spatial stability

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doi: 10.1016/j.ultramic.2018.05.005.

Q&A session

Please type in the questions you have
in the Q&A box and press ***Send***.



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